

IGBT Chip in NPT-technology

FEATURES:

- 600V NPT technology
- 100μm chip
- positive temperature coefficient
- easy paralleling

This chip is used for:

IGBT Modules



Applications:

• drives

Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC25T60NC	600V	30A	4.5 x 5.71 mm ²	sawn on foil	Q67050-A4143- A001

MECHANICAL PARAMETER:

Raster size	4.5 x 5.71				
Area total / active	25.69 / 21.4				
Emitter pad size	2x(2.18x1.58)				
Gate pad size	0.68 x 1.08				
Thickness	100	μm			
Wafer size	150	mm			
Flat position	270	deg			
Max.possible chips per wafer	566				
Passivation frontside	Photoimide				
Emitter metallization	3200 nm Al Si 1%				
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	AI, ≤500μm				
Reject Ink Dot Size	Ø 0.65mm; max 1.2mm				
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T_j =25 °C	V _{CE}	600	V
DC collector current, limited by T _{jmax}	I _C	1)	Α
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	90	Α
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T_j , T_{stg}	-55 + 150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
rarameter			min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	V_{GE} =0 V , I_{C} =1000 μA	600			
Collector-emitter saturation voltage	V _{CE(sat)}	V_{GE} =15V, I_{C} =30A	1.7	2.0	2.5	V
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=700\mu A,\ V_{GE}=V_{CE}$	4.5	5.5	6.5	
Zero gate voltage collector current	I _{CES}	V_{CE} =600V, V_{GE} =0V			2.1	μΑ
Gate-emitter leakage current	I _{GES}	$V_{CE}=0V$, $V_{GE}=20V$			120	nA

DYNAMIC CHARACTERISTICS (tested at component):

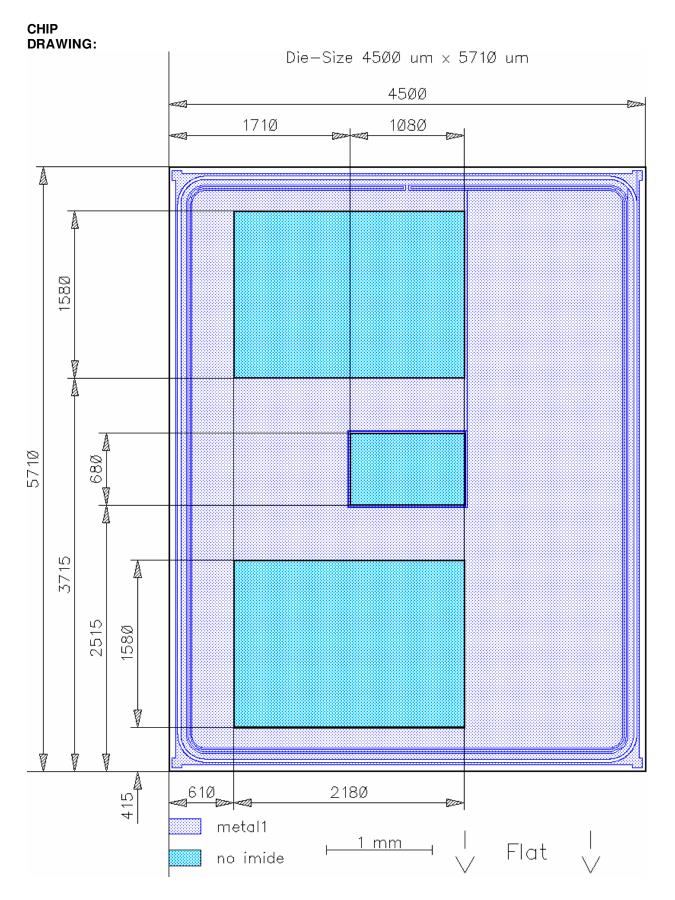
Parameter	Symbol	Conditions	Value			Unit
raiailletei			min.	typ.	max.]
Input capacitance	Ciss	V _{CE} =25V	-	1350		pF
Output capacitance	Coss	$V_{GE}=0V$	-	tbd		
Reverse transfer capacitance	C_{rss}	f=1 M Hz	-	120		

SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

Parameter	Symbol	Conditions 1)	Value			Unit
- arameter			min.	typ.	max.	
Turn-on delay time	$t_{d(on)}$	$T_{\rm j} = 125 ^{\circ} ^$	-	21		ns
Rise time	t _r	I _C =30A	-	8		
Turn-off delay time	$t_{d(off)}$	$V_{\rm GE}=\pm 15 \rm V$ $R_{\rm G}=8.2 \Omega$	-	110		
Fall time	t_{f}	, rig=0.232	-	25		

¹⁾ values also influenced by parasitic L- and C- in measurement and package.







FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

FS 30 R06 XL4

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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